

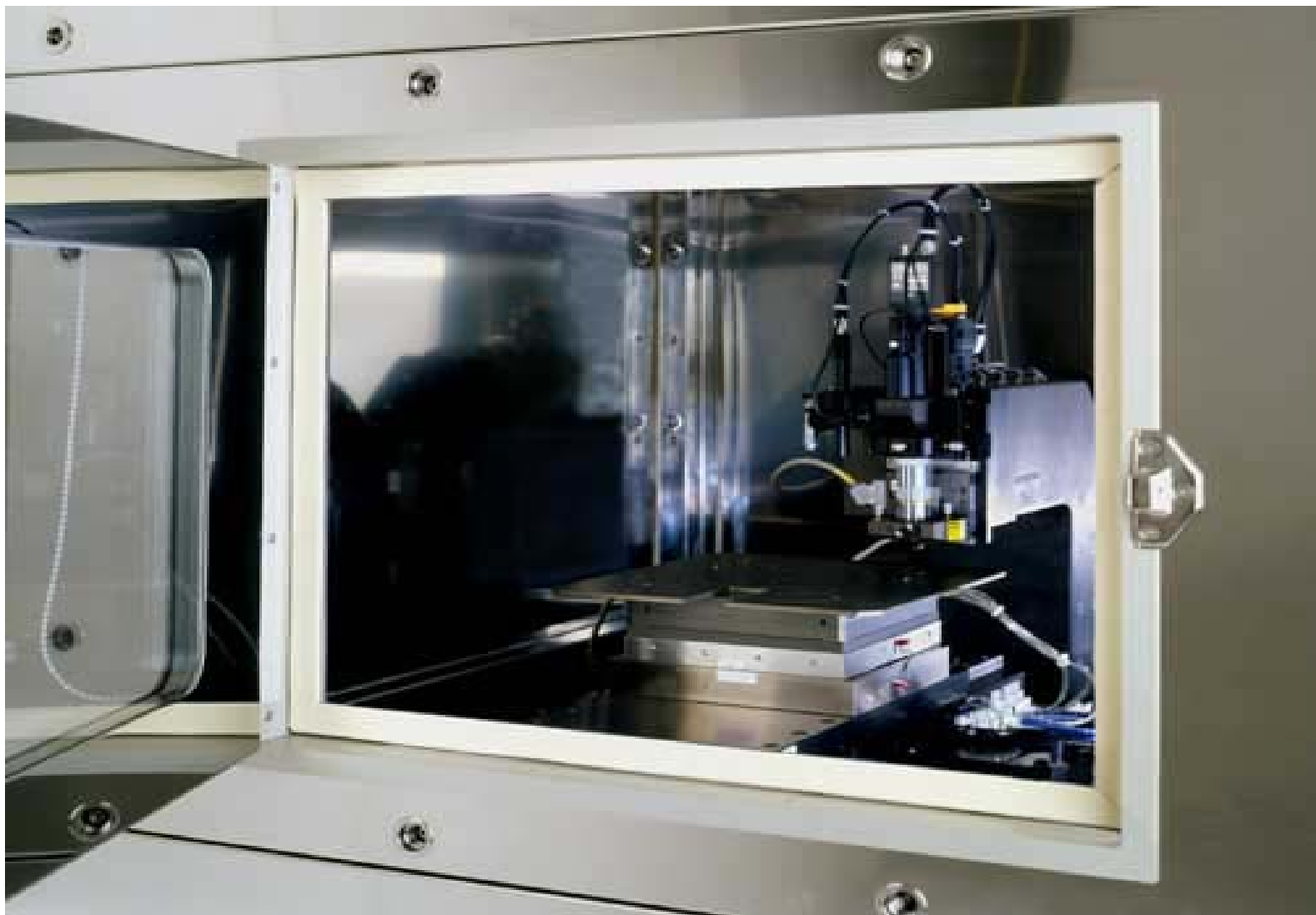
PSIA XE-300P



XE-300P



XE-300P



XE-300P Specifications

Long Range Profiler

- Max Range: 10mm
- Max out of axis deviation: 5nm
- Avg out of axis deviation: <2nm
- Data Points: 64,000/line

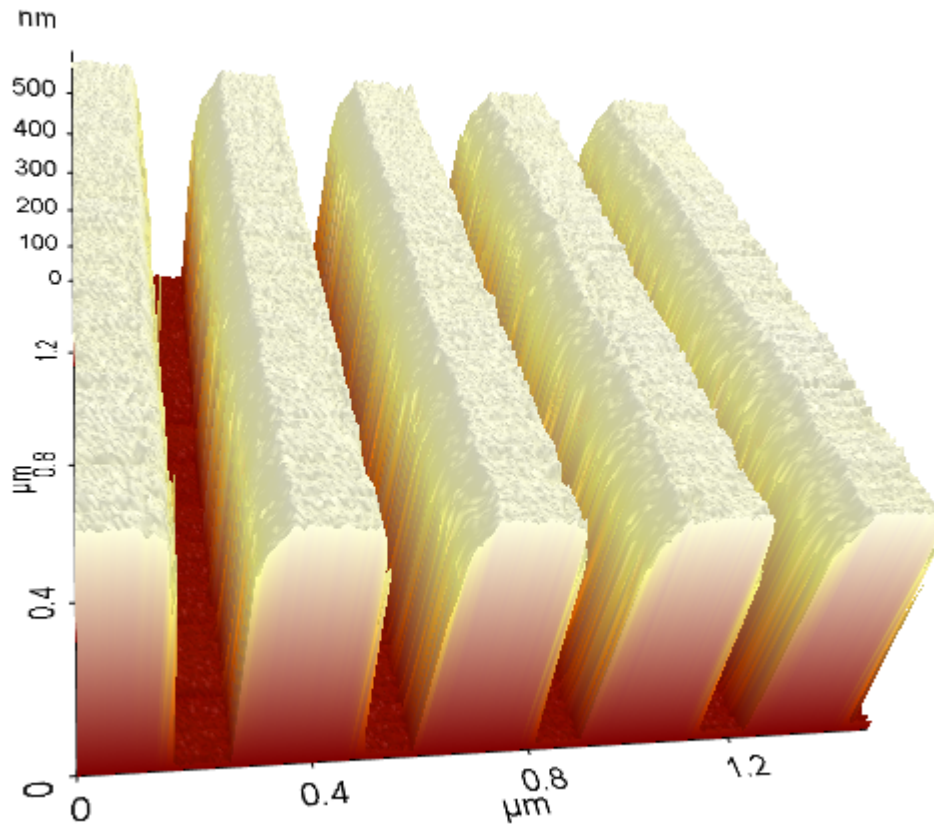
XE-AFM

- Max Range: 100 μ m x 100 μ m
- Lateral Resolution: < 0.15nm
- Height Resolution: 0.05nm

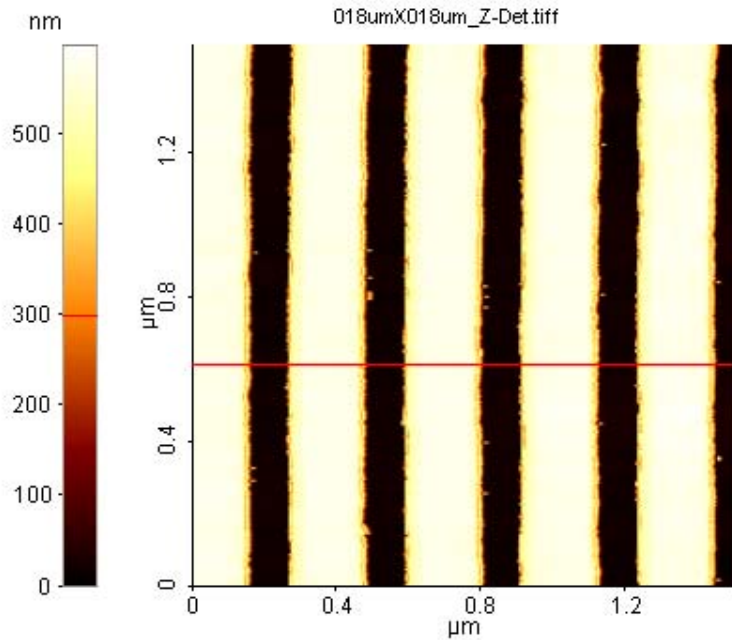
KEY Features

- Long Range Profile Capability
- Automatic Wafer Handling System W/SMIF
- Cognex Vision/ Alignment System
- Distortion-free XE-AFM Scan System
- Mini-environment with ULPA
- Active Vibration Isolation System
- Class 10 Clean Room Compatible

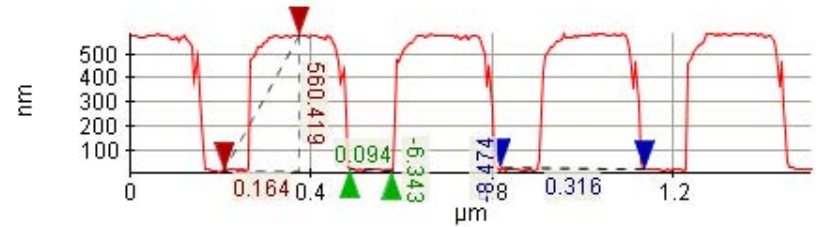
0.18um X 0.18um – Z detector image



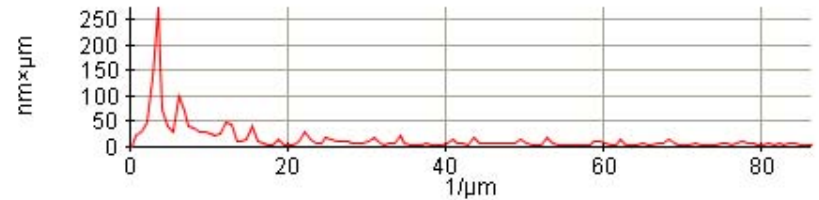
0.18um X 0.18um – Z detector image



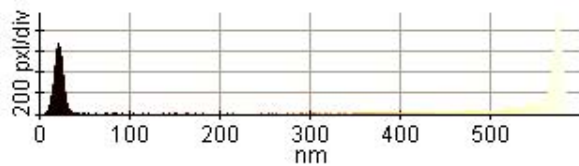
Line Profile: Red



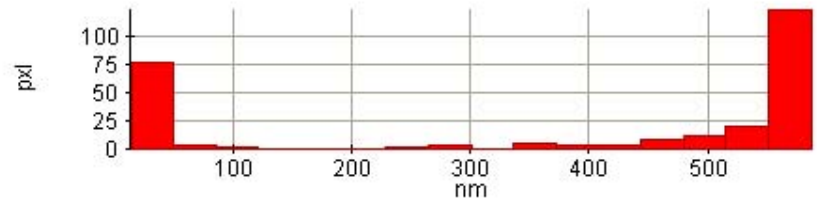
Power Spectrum: Red



Histogram



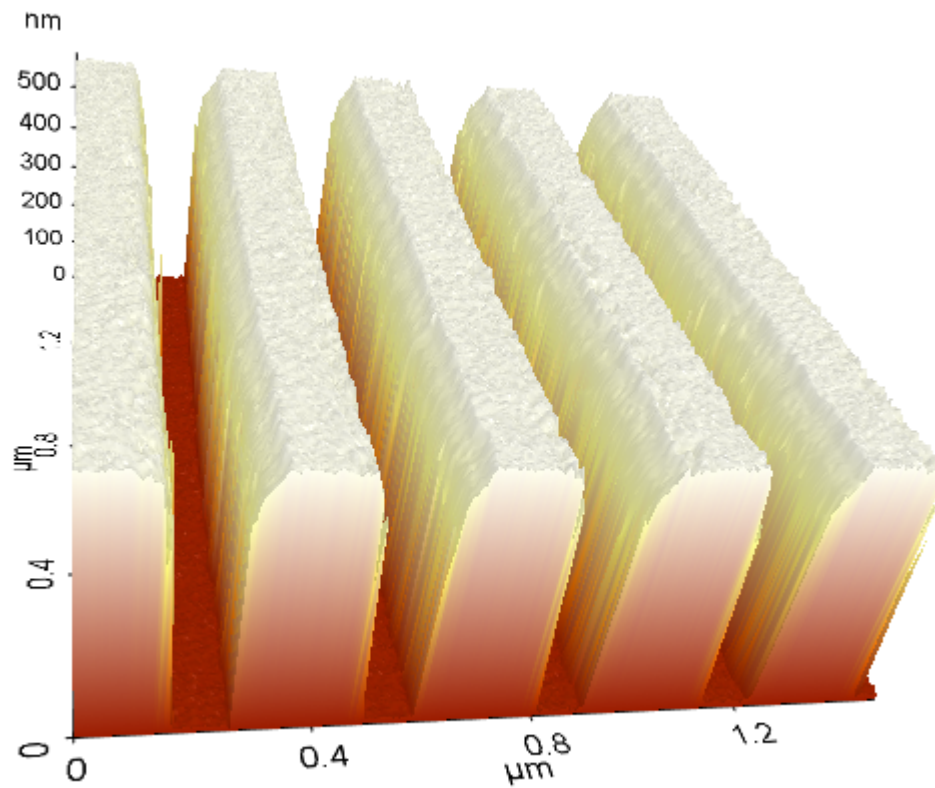
Line Histogram: Red



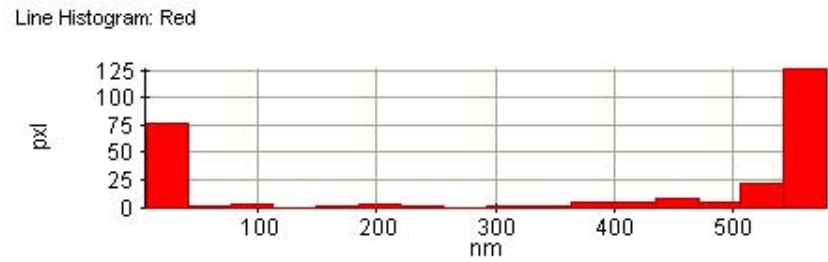
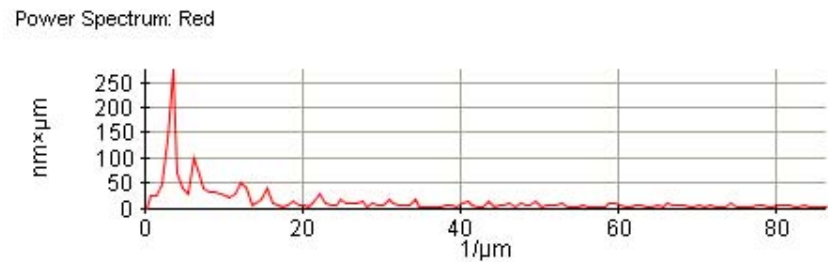
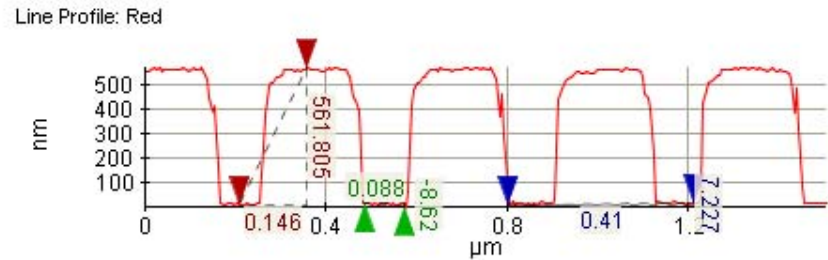
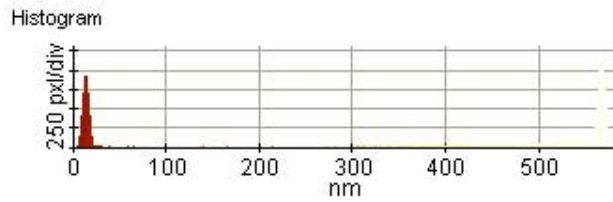
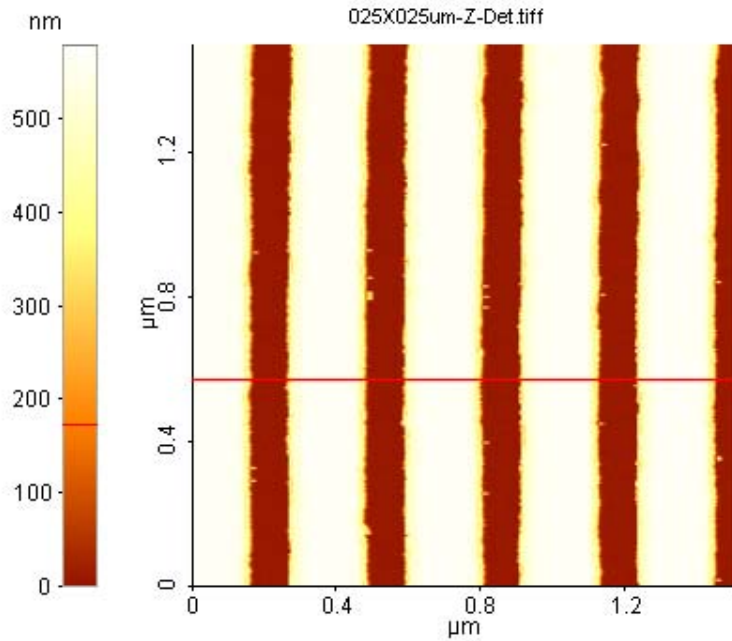
Statistics

Line	Min(nm)	Max(nm)	Mid(nm)	Mean(nm)	Rpv(nm)	Rq(nm)	Ra(nm)
Red	12.472	585.440	298.956	379.186	572.968	247.103	228.490

0.25um X 0.25um – Z detector image



0.25um X 0.25um – Z detector image



Statistics

Line	Min(nm)	Max(nm)	Mid(nm)	Mean(nm)	Rpv(nm)	Rq(nm)	Ra(nm)
Red	3.788	577.099	290.443	371.910	573.311	246.541	227.869